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28TH IEEE EUROPEAN TEST SYMPOSIUM 2023

MAY 22-26 IN VENICE, ITALY | HYBRID CONFERENCE

The IEEE European Test Symposium (ETS) 2023 seeks original, unpublished contributions of the following types:

- **Scientific Papers**, up to 6 pages, for inclusion in the Formal IEEE Proceedings
- **Industrial Papers**, up to 6 pages, for inclusion in the Informal Digest of Papers
- **Fringe Workshops** proposals about relevant and timely topics.

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- **DFT AND TEST ACCESS STANDARDS**
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- **VALIDATION, VERIFICATION DEBUG AND DIAGNOSIS**
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Key Dates:

December 9, 2022:
December 16, 2022:
February 6, 2023:

abstract submission
final pdf submission
authors notification

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